

# **MOSFET** – Power, N-Channel

## 80 V, 3.6 m $\Omega$

## **NVCR4LS3D6N08M7A**

#### **Features**

- Typical  $R_{DS(on)} = 2.8 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$
- Typical  $Q_{g(tot)} = 68 \text{ nC}$  at  $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified
- RoHS Compliant

### DIMENSION (µm)

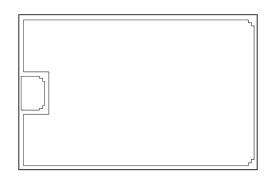
Die Size	3810×2463.8
Die Size (Sawn)	$3790 \pm 15 \times 2443.8 \pm 15$
Source Attach Area	3606.3 × 2236.4
Gate Attach Area	359.9 × 517.5
Die Thickness	101.6 ±19.1

Gate and Source: AlSiCu

Drain: Ti-NiV-Ag (back side of die)

Passivation: Polyimide Wafer Diameter: 8 inch Wafer Sawn on UV Tape Bad Dice Identified in Inking Gross Die Counts: 2768

The Chip is 100% Probed to Meet the Conditions and Limits Specified at  $T_J$  = 25°C.



#### **ORDERING INFORMATION**

Device	Package		
NVCR4LS3D6N08M7A	Wafer		
	Sawn on Foil		

#### **RECOMMENDED STORAGE CONDITIONS**

Temperature	22 to 28°C
RH	40 to 66%

Symbol	Parameter	Condition	Тур	Max	Unit	
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	-	4.0	V
*R <sub>DS(on)</sub>	Bare Die Drain to Source On Resistance	I <sub>D</sub> = 5 A, V <sub>GS</sub> = 10 V	-	2.8	3.6	mΩ
V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 5 A, V <sub>GS</sub> = 0 V	-	-	1.2	V
E <sub>AS</sub>	Single Pulse Drain-to-Source Avalanche Energy	L = 3 mH, I <sub>AS</sub> = 16.6 A	413	_	-	mJ

<sup>\*</sup>Accurate R<sub>DS(on)</sub> test at die level is not feasible for this thin die as limited by the test contact precision attainable in a die form. The max R<sub>DS(on)</sub> specification is defined from the historical performance of the die in package but is not guaranteed by test in production. The die R<sub>DS(on)</sub> performance depends on the Source wire/ribbon bonding layout.

1

## MOSFET MAXIMUM RATINGS in Reference to the FDDL86367-F085 electrical data in D-PAK

(T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit
V <sub>DSS</sub>	Drain to Source Voltage	80	V
$V_{GS}$	Gate to Source Voltage	±20	V
I <sub>D</sub>	Continuous Drain Current $R_{\theta JC}$ ( $V_{GS}$ = 10) (Note 1) $T_{C}$ = 25°C $T_{C}$ = 100°C	164 116	A
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	82	mJ
P <sub>D</sub>	Power Dissipation $R_{\theta JC}$	227	W
	Derate Above 25°C	1.5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to +175	°C
$R_{ heta JC}$	Thermal Resistance, Junction to Case	0.66	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (Note 3)	52	°C/W

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Current is limited by silicon.
- 2. Starting  $T_J = 25^{\circ}C$ ,  $L = 40 \,\mu\text{H}$ ,  $I_{AS} = 64 \,\text{A}$ ,  $V_{DD} = 80 \,\text{V}$  during inductor charging and  $V_{DD} = 0 \,\text{V}$  during time in avalanche. 3.  $R_{\theta JA}$  is the sum of the junction–to–case and case–to–ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in<sup>2</sup> pad of 2oz copper.

#### **ELECTRICAL CHARACTERISTICS** in Reference to the FDDL86367–F085 electrical data in D-PAK (T<sub>1</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
OFF CHARAC	CTERISTICS						
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A},  V_{GS} = 0 \text{V}$		80	-	-	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C	_	-	1	μΑ
			T <sub>J</sub> = 175°C (Note 4)	_	-	1	mA
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V	•	_	-	±100	nA
ON CHARAC	TERISTICS						
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	2.0	3.0	4.0	V
R <sub>DS(on)</sub>	Drain to Source on Resistance	I <sub>D</sub> = 80 A,	T <sub>J</sub> = 25°C	_	3.3	4.2	mΩ
	V <sub>GS</sub> = 10 V	V <sub>GS</sub> = 10 V	T <sub>J</sub> = 175°C (Note 4)	_	6.6	8.4	mΩ
DYNAMIC CH	ARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V, f = 1 MHz		_	4840	-	pF
C <sub>oss</sub>	Output Capacitance			-	814	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			_	31	-	pF
R <sub>g</sub>	Gate Resistance	f = 1 MHz		_	2.3	-	Ω
Q <sub>g(ToT)</sub>	Total Gate Charge	V <sub>GS</sub> = 0 to 10 V, V <sub>DD</sub> = 40 V, I <sub>D</sub> = 80 A		_	68	-	nC
Q <sub>g(th)</sub>	Threshold Gate Charge	V <sub>GS</sub> = 0 to 2 V, V <sub>DD</sub> = 40 V, I <sub>D</sub> = 80 A		_	8.8	-	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 80 A		_	22	-	nC
$Q_{qd}$	Gate to Drain "Miller" Charge			1	14	-	nC
SWITCHING (	CHARACTERISTICS						
t <sub>d(on)</sub>	Turn-On Delay	$V_{DD} = 40 \text{ V}, I_{D}$		-	20	-	ns
t <sub>r</sub>	Rise Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		_	49	-	ns
t <sub>d(off)</sub>	Turn-Off Delay			-	36	-	ns
t <sub>f</sub>	Fall Time			_	16	_	ns
DRAIN-SOUF	RCE DIODE CHARACTERISTIC	•			•		•
V <sub>SD</sub> Source to	Source to Drain Diode Voltage	I <sub>SD</sub> = 80 A, V <sub>G</sub>	S = 0 V	-	-	1.3	V
		I <sub>SD</sub> = 40 A, V <sub>G</sub>		-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 80 \text{ A}, dI_{SD}/dt = 100 \text{ A}/\mu\text{s}, \\ V_{DD} = 64 \text{ V}$		-	68	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge			-	66	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>4.</sup> The maximum value is specified by design at T<sub>J</sub> = 175°C. Product is not tested to this condition in production.

#### **TYPICAL CHARACTERISTICS**

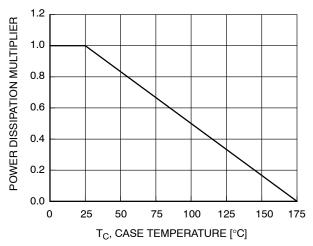


Figure 1. Normalized Power Dissipation vs. Case Temperature

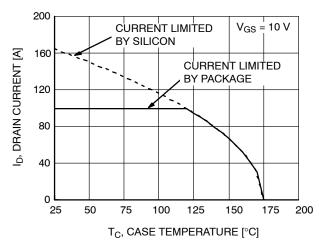


Figure 2. Maximum Continuous Drain Current vs. Case Temperature

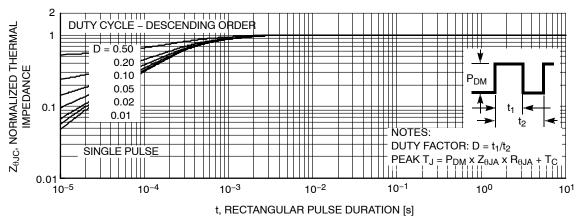


Figure 3. Normalized Maximum Transient Thermal Impedance

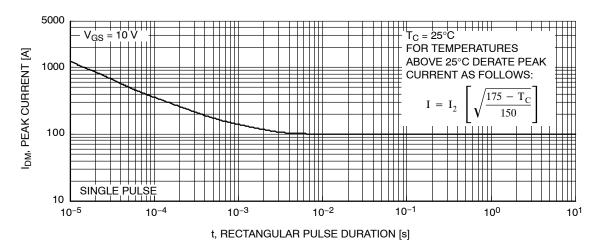


Figure 4. Peak Current Capability

#### TYPICAL CHARACTERISTICS (continued)

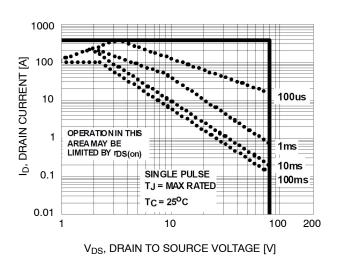


Figure 5. Forward Bias Safe Operating Area

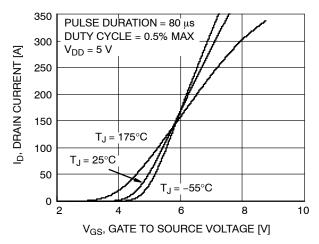


Figure 7. Transfer Characteristics

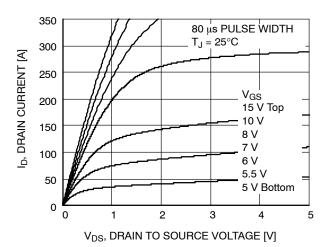
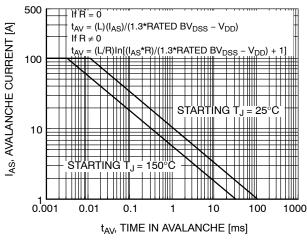


Figure 9. Saturation Characteristics



(Note: Refer to **onsemi** Applications Notes <u>AN7514</u> and <u>AN7515</u>)

Figure 6. Unclamped Inductive Switching Capability

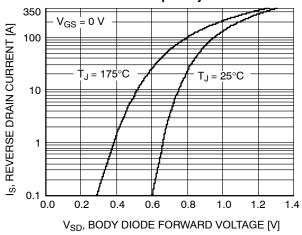


Figure 8. Forward Diode Characteristics

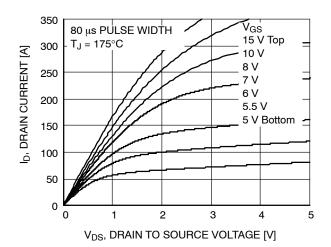


Figure 10. Saturation Characteristics

#### TYPICAL CHARACTERISTICS (continued)

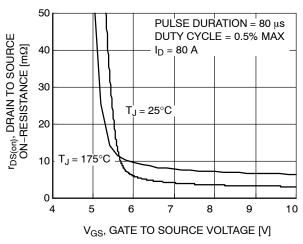


Figure 11. R<sub>DSON</sub> vs. Gate Voltage

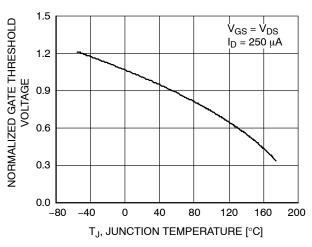


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

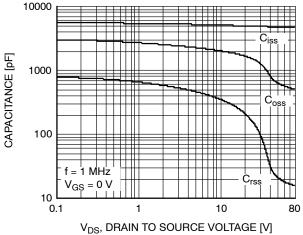


Figure 15. Capacitance vs. Drain to Source Voltage

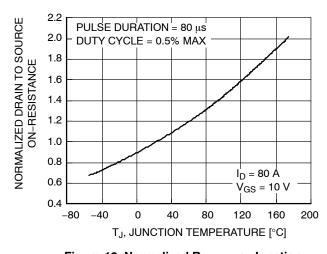


Figure 12. Normalized R<sub>DSON</sub> vs. Junction Temperature

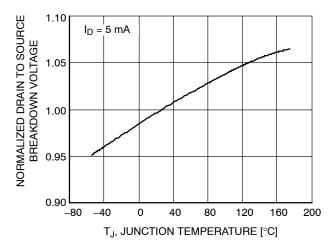


Figure 14. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

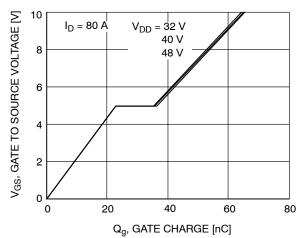


Figure 16. Gate Charge vs. Gate to Source Voltage

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